IXYS

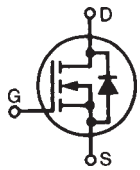
High Current MegaMOS™ FET

IXTK 80N25

V_{DSS} = 250 V
I_{D25} = 80 A
$R_{DS(on)}$ = 33 mΩ

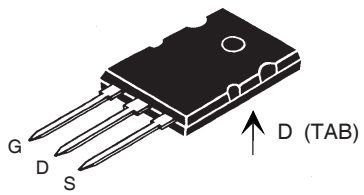
N-Channel Enhancement Mode

Preliminary Data Sheet



Symbol	Test conditions	Maximum ratings	
V_{DSS}	T_J = 25°C to 150°C	250	V
V_{DGR}	T_J = 25°C to 150°C; R_{GS} = 1.0 MΩ	250	V
V_{GS}	Continuous	±20	V
V_{GSM}	Transient	±30	V
I_{D25}	T_C = 25°C MOSFET chip capability	80	A
$I_{D(RMS)}$	External lead current limit	75	A
I_{DM}	T_C = 25°C, pulse width limited by T_{JM}	320	A
I_{AR}	T_C = 25°C	80	A
E_{AR}	T_C = 25°C	60	mJ
E_{AS}	T_C = 25°C	2.5	J
dv/dt	$I_S \le I_{DM}$, di/dt ≤ 100 A/μs, $V_{DD} \le V_{DSS}$ $T_J \le$ 150°C, R_G = 2 Ω	5	V/ns
P_D	T_C = 25°C	540	W
T_J		-55 ... +150	°C
T_{JM}		150	°C
T_{stg}		-55 ... +150	°C
T_L	1.6 mm (0.063 in.) from case for 10 s	300	°C
M_d	Mounting torque	0.7/6	Nm/lb.in.
Weight	TO-264	10	g

TO-264 AA (IXTK)



G = Gate D = Drain
S = Source Tab = Drain

Features

- Low $R_{DS(on)}$ HDMOS™ process
- Rugged polysilicon gate cell structure
- International standard package
- Fast switching times

Applications

- Motor controls
- DC choppers
- Switched-mode power supplies

Advantages

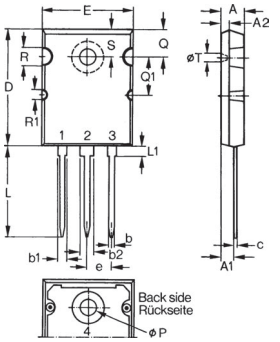
- Easy to mount with one screw (isolated mounting screw hole)
- Space savings
- High power density

Symbol	Test Conditions (T_J = 25°C unless otherwise specified)		Characteristic Values Min.	Typ.	Max.	
V_{DSS}	V_{GS} = 0 V, I_D = 1 mA		250			V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, I_D = 250 μA		2.0		4.0	V
I_{GSS}	V_{GS} = ±20 V DC, V_{DS} = 0				±100	nA
I_{DSS}	$V_{DS} = V_{DSS}$	T_J = 25°C			50	μA
	V_{GS} = 0 V	T_J = 125°C			2	mA
$R_{DS(on)}$	V_{GS} = 10 V, $I_D = 0.5\ I_{D25}$ Pulse test, t ≤ 300 ms, duty cycle d ≤ 2%				33	mΩ

© 2003 IXYS All rights reserved

Symbol	Test Conditions (T_J = 25°C unless otherwise specified)	Characteristic values Min.	Typ.	Max.	
g_{fs}	V_{DS} = 10 V; I_D = 0.5 I_{D25}, pulse test	40	56		S
C_{iss}	V_{GS} = 0 V, V_{DS} = 25 V, f = 1 MHz		6000		pF
C_{oss}			1125		pF
C_{rss}			420		pF
$t_{d(on)}$	V_{GS} = 10 V, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25} R_G = 1.0 Ω (External)		28		ns
t_r			25		ns
$t_{d(off)}$			88		ns
t_f			24		ns
$Q_{g(on)}$	V_{GS} = 10 V, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25}		240		nC
Q_{gs}			40		nC
Q_{gd}			110		nC
R_{thJC}				0.23	K/W
R_{thCK}			0.15		K/W

TO-264 AA Outline



Dim.	Millimeter Min.	Max.	Inches Min.	Max.
A	4.82	5.13	.190	.202
A1	2.54	2.89	.100	.114
A2	2.00	2.10	.079	.083
b	1.12	1.42	.044	.056
b1	2.39	2.69	.094	.106
b2	2.90	3.09	.114	.122
c	0.53	0.83	.021	.033
D	25.91	26.16	1.020	1.030
E	19.81	19.96	.780	.786
e	5.46 BSC		.215 BSC	
J	0.00	0.25	.000	.010
K	0.00	0.25	.000	.010
L	20.32	20.83	.800	.820
L1	2.29	2.59	.090	.102
P	3.17	3.66	.125	.144
Q	6.07	6.27	.239	.247
Q1	8.38	8.69	.330	.342
R	3.81	4.32	.150	.170
R1	1.78	2.29	.070	.090
S	6.04	6.30	.238	.248
T	1.57	1.83	.062	.072

Source-Drain Diode **Ratings and Characteristics** (T_J = 25°C unless otherwise specified)

Symbol	Test Conditions	Min.	Typ.	Max.	
I_S	V_{GS} = 0V			80	A
I_{SM}	Repetitive; pulse width limited by T_{JM}			320	A
V_{SD}	I_F = I_S, V_{GS} = 0 V, Pulse test, t ≤ 300 µs, duty cycle d ≤ 2 %			1.5	V
t_{rr}	I_F = 25A, -di/dt = 100 A/µs, V_R = 100V		300		ns
Q_{rr}			3.0		µC

IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,881,106 5,017,508 5,049,961 5,187,117 5,486,715 6,306,728B1 6,259,123B1 6,306,728B1 4,850,072 4,931,844 5,034,796 5,063,307 5,237,481 5,381,025 6,404,065B1 6,162,665 6,534,343 6,583,505

Fig. 1. Output Characteristics @ 25 Deg. C

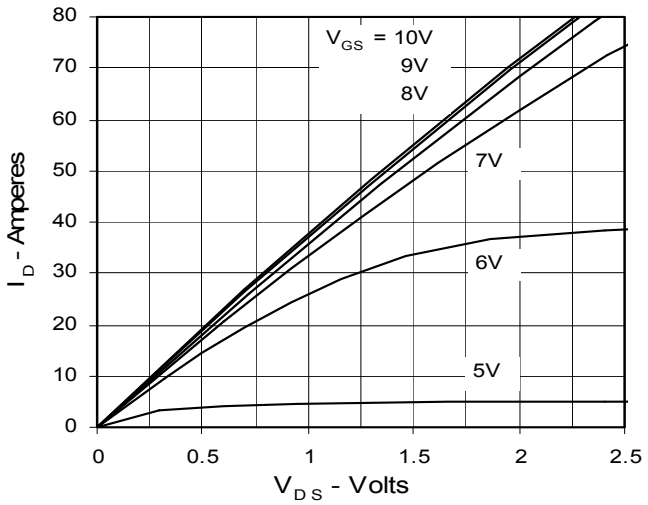


Fig. 2. Extended Output Characteristics @ 25 deg. C

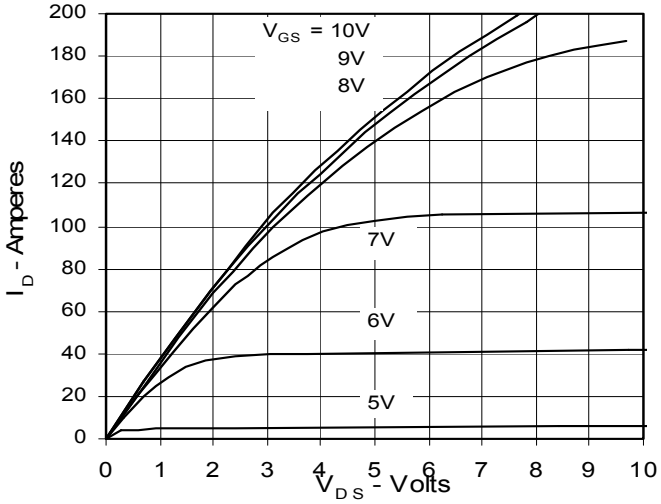


Fig. 3. Output Characteristics @ 125 Deg. C

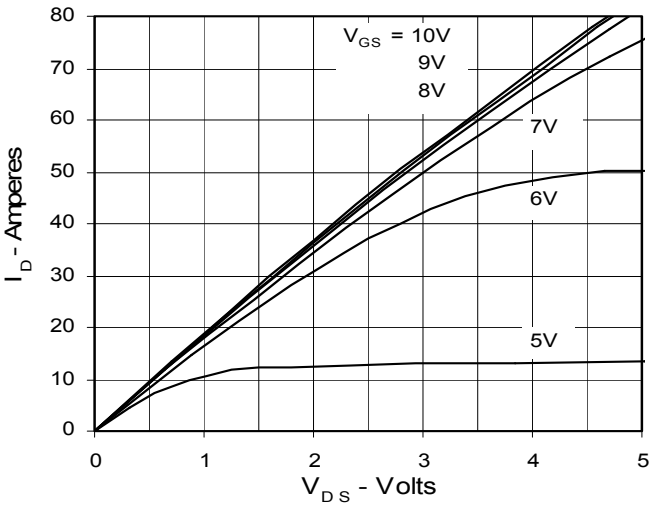


Fig. 4. $R_{DS(on)}$ Normalized to I_{D25} Value vs. Junction Temperature

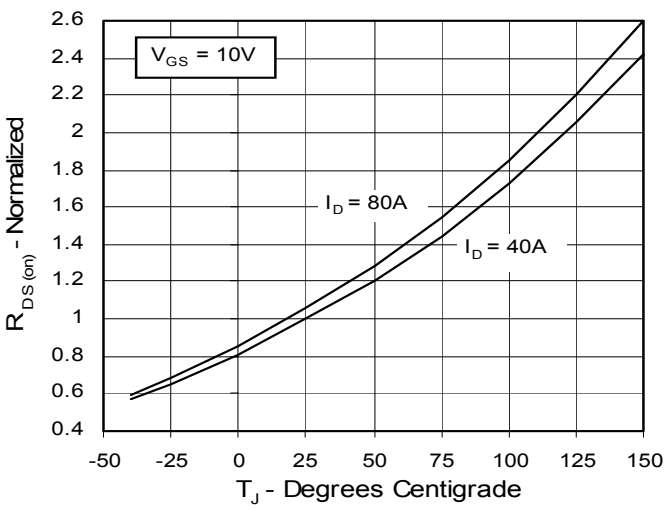


Fig. 5. $R_{DS(on)}$ Normalized to I_{D25} Value vs. I_D

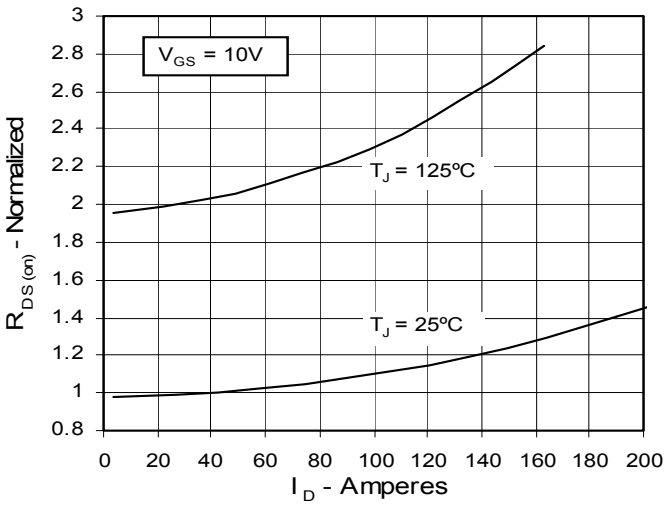
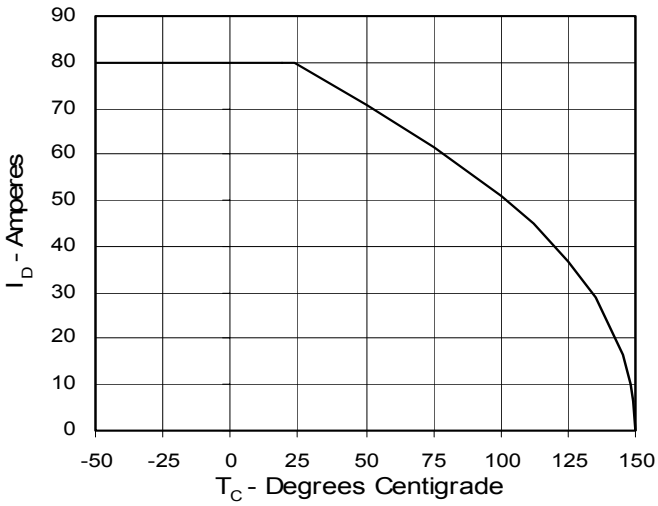


Fig. 6. Drain Current vs. Case Temperature



© 2003 IXYS All rights reserved

Fig. 7. Input Admittance

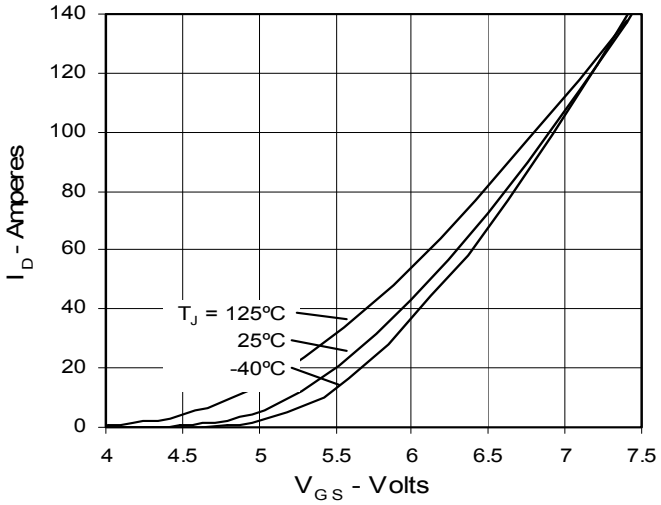


Fig. 8. Transconductance

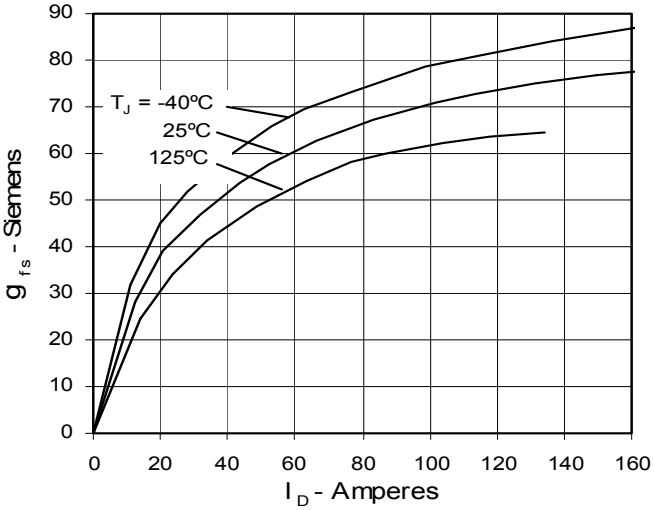


Fig. 9. Source Current vs. Source-To-Drain Voltage

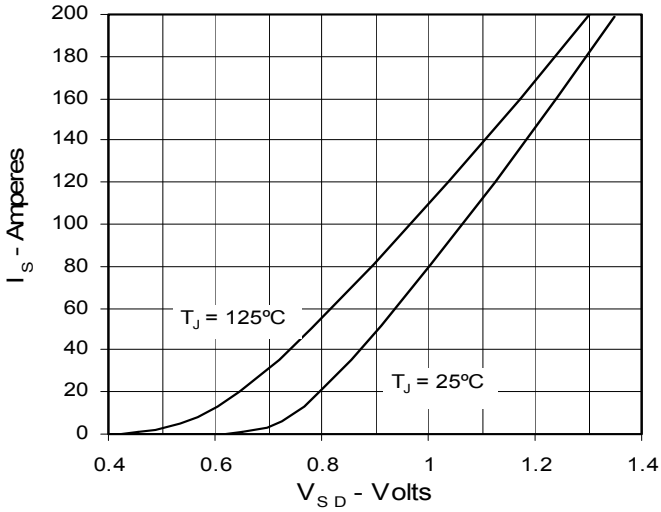


Fig. 10. Gate Charge

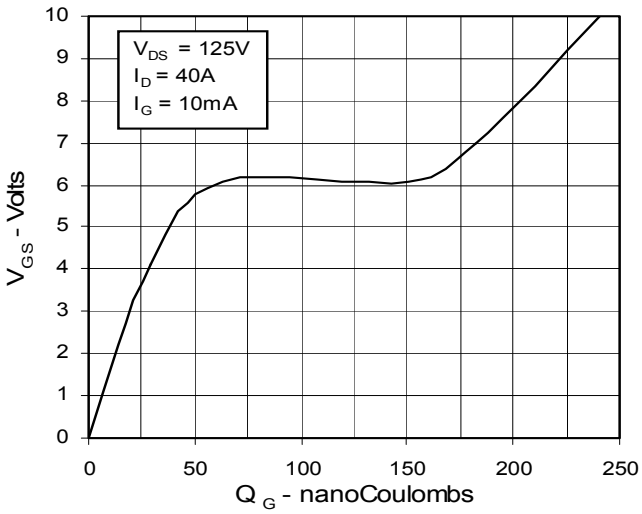


Fig. 11. Capacitance

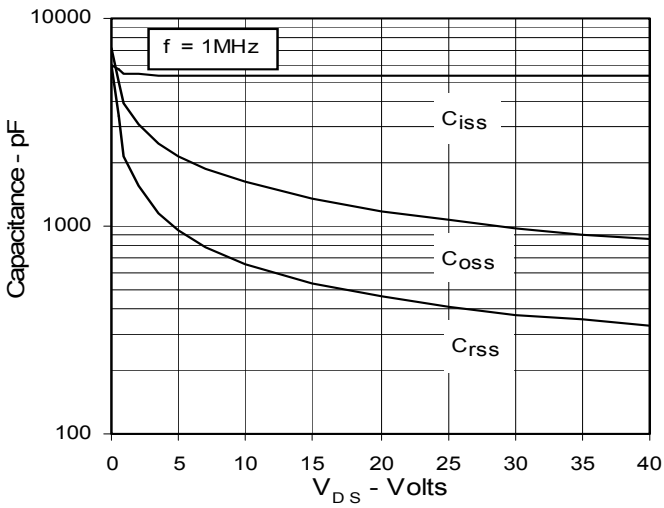
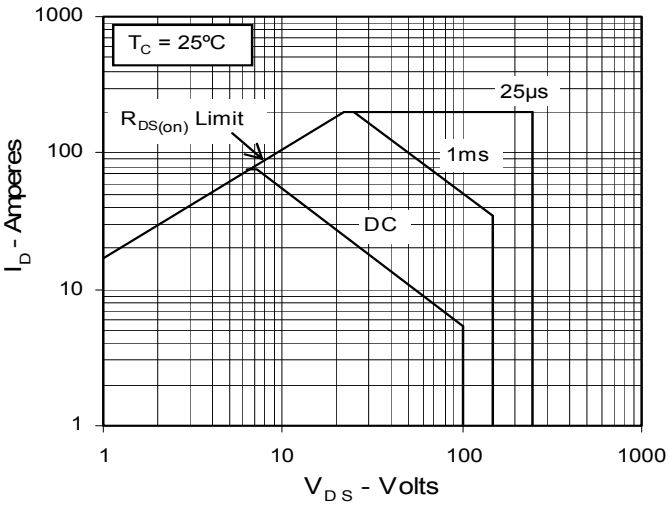
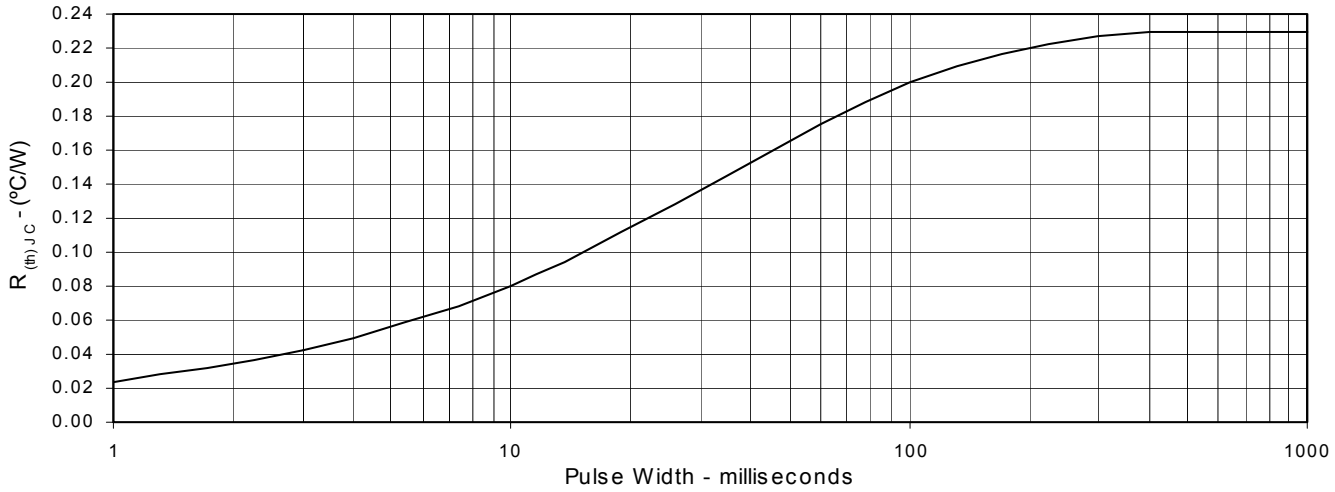


Fig. 12. Forward Bias Safe Operating Area



IXYS reserves the right to change limits, test conditions, and dimensions.

Fig. 13. Forward Biased Safe Operating Area (FBSOA)



© 2003 IXYS All rights reserved